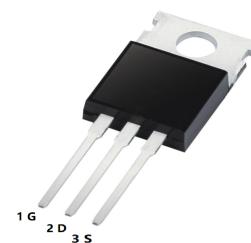


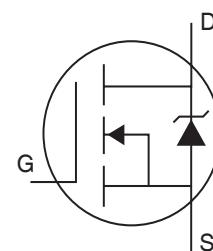
## Applications

- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits



## Benefits

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dl/dt Capability
- Lead-Free
- Halogen-Free
- $V_{DS} = 100V$
- $I_D = 120A$
- $R_{DS(ON)}$ (at  $V_{GS}=10V$ ) <6mΩ



## Absolute Maximum Ratings

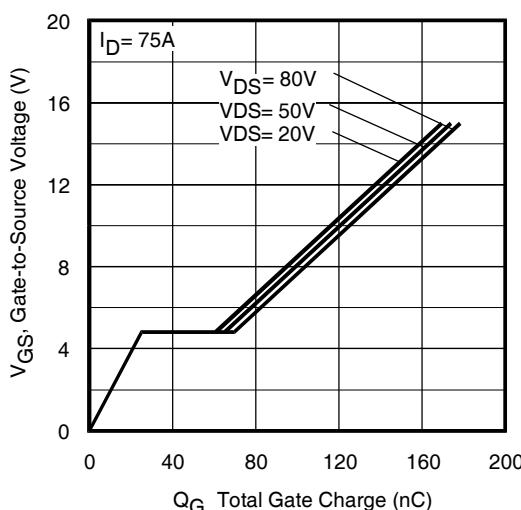
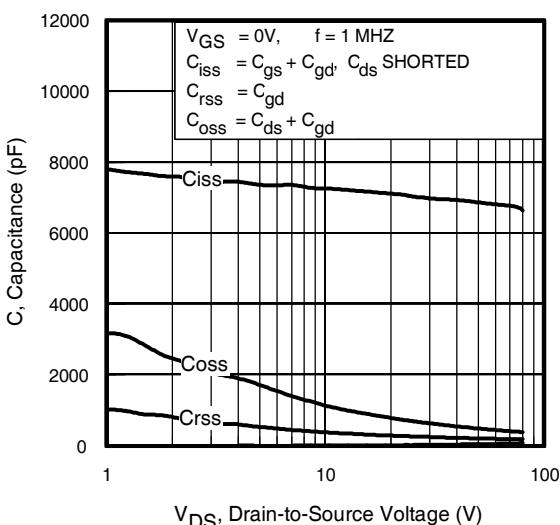
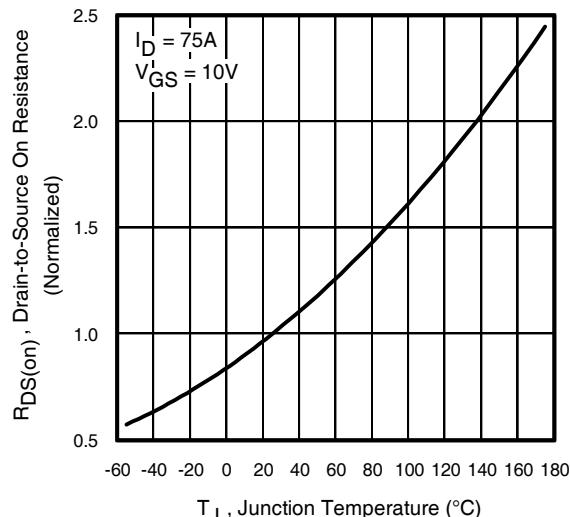
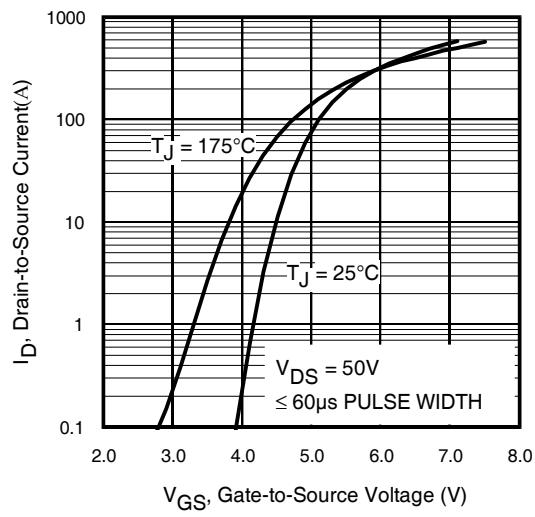
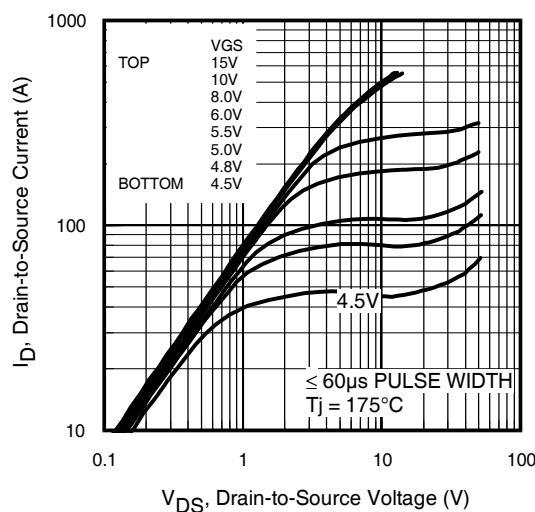
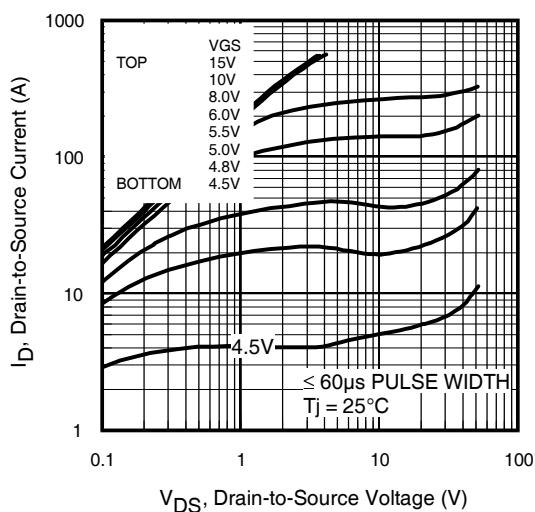
Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	127①	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	90①	
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Wire Bond Limited)	120	
$I_{DM}$	Pulsed Drain Current ②	560	
$P_D @ T_C = 25^\circ C$	Maximum Power Dissipation	250	W
	Linear Derating Factor	1.7	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
$dv/dt$	Peak Diode Recovery ④	18	V/ns
$T_J$	Operating Junction and	-55 to +175	°C
$T_{STG}$	Storage Temperature Range		
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting torque, 6-32 or M3 screw	10lb-in (1.1N·m)	
$E_{AS}$ (Thermally limited)	Single Pulse Avalanche Energy ③	130	mJ
$I_{AR}$	Avalanche Current ①	See Fig. 14, 15, 22a, 22b,	A
$E_{AR}$	Repetitive Avalanche Energy ⑤		mJ
Symbol	Parameter	Typ.	Max.
$R_{θJC}$	Junction-to-Case ⑥	0.6	°C/W
$R_{θCS}$	Case-to-Sink, Flat Greased Surface	0.50	
$R_{θJA}$	Junction-to-Ambient ⑦⑧	62	

Static @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.11		V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 5\text{mA}$ ②
$R_{DS(on)}$	Static Drain-to-Source On-Resistance		4.8	6.0	m $\Omega$	$V_{GS} = 10V, I_D = 75\text{A}$ ⑤
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_D = 150\mu\text{A}$
$I_{\text{DSS}}$	Drain-to-Source Leakage Current			20	$\mu\text{A}$	$V_{DS} = 100V, V_{GS} = 0V$
				250		$V_{DS} = 80V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-100		$V_{GS} = -20V$
$R_G$	Internal Gate Resistance		0.7		$\Omega$	
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$g_{fs}$	Forward Transconductance	150			S	$V_{DS} = 50V, I_D = 75\text{A}$
$Q_g$	Total Gate Charge		120	170	nC	$I_D = 75\text{A}$
$Q_{gs}$	Gate-to-Source Charge		29			$V_{DS} = 50V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		35			$V_{GS} = 10V$ ⑤
$Q_{\text{sync}}$	Total Gate Charge Sync. ( $Q_g - Q_{gd}$ )		85			$I_D = 75\text{A}, V_{DS} = 0V, V_{GS} = 10V$
$t_{d(on)}$	Turn-On Delay Time		20		ns	$V_{DD} = 65V$
$t_r$	Rise Time		60			$I_D = 75\text{A}$
$t_{d(off)}$	Turn-Off Delay Time		55			$R_G = 2.7\Omega$
$t_f$	Fall Time		57			$V_{GS} = 10V$ ⑤
$C_{iss}$	Input Capacitance		6860		pF	$V_{GS} = 0V$
$C_{oss}$	Output Capacitance		490			$V_{DS} = 50V$
$C_{rss}$	Reverse Transfer Capacitance		220			$f = 1.0\text{MHz}$ , See Fig. 5
$C_{oss \text{ eff. (ER)}}$	Effective Output Capacitance (Energy Related)		570			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 80V$ ⑦, See Fig. 11
$C_{oss \text{ eff. (TR)}}$	Effective Output Capacitance (Time Related)⑥		920			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 80V$ ⑥
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_s$	Continuous Source Current (Body Diode)			127①	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode) ②			560	A	
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^\circ\text{C}, I_S = 75\text{A}, V_{GS} = 0V$ ⑤
$t_{rr}$	Reverse Recovery Time		40		ns	$T_J = 25^\circ\text{C} \quad V_R = 85V,$
			49			$T_J = 125^\circ\text{C} \quad I_F = 75\text{A}$
$Q_{rr}$	Reverse Recovery Charge		58		nC	$T_J = 25^\circ\text{C} \quad \frac{di}{dt} = 100\text{A}/\mu\text{s}$ ⑤
			89			$T_J = 125^\circ\text{C}$
$I_{RRM}$	Reverse Recovery Current		2.5		A	$T_J = 25^\circ\text{C}$
$t_{on}$	Forward Turn-On Time					Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)

## Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 120A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ Limited by  $T_{J\text{max}}$ , starting  $T_J = 25^\circ\text{C}$ ,  $L = 0.047\text{mH}$   $R_G = 25\Omega$ ,  $I_{AS} = 75\text{A}$ ,  $V_{GS} = 10V$ . Part not recommended for use above the Eas value and test conditions.
- ④  $I_{SD} \leq 75\text{A}$ ,  $di/dt \leq 600\text{A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(\text{BR})\text{DSS}}$ ,  $T_J \leq 175^\circ\text{C}$ .
- ⑤ Pulse width  $\leq 400\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ⑥  $C_{oss \text{ eff. (TR)}}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- ⑦  $C_{oss \text{ eff. (ER)}}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- ⑧  $R_\theta$  is measured at  $T_J$  approximately  $90^\circ\text{C}$ .



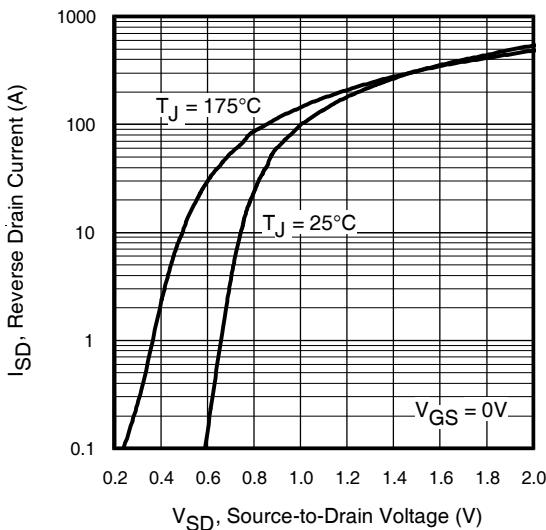


Fig 7. Typical Source-Drain Diode Forward Voltage

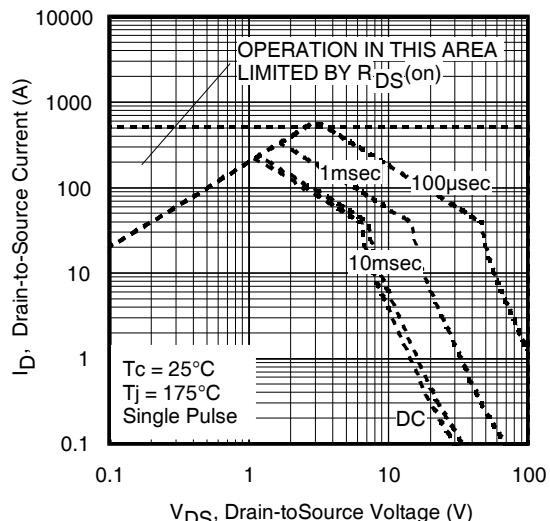


Fig 8. Maximum Safe Operating Area

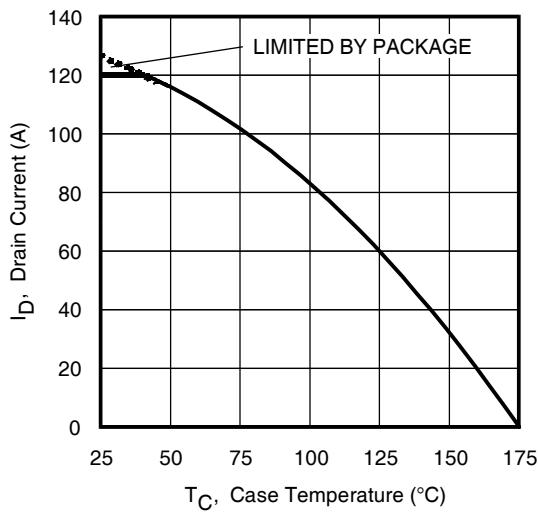


Fig 9. Maximum Drain Current vs. Case Temperature

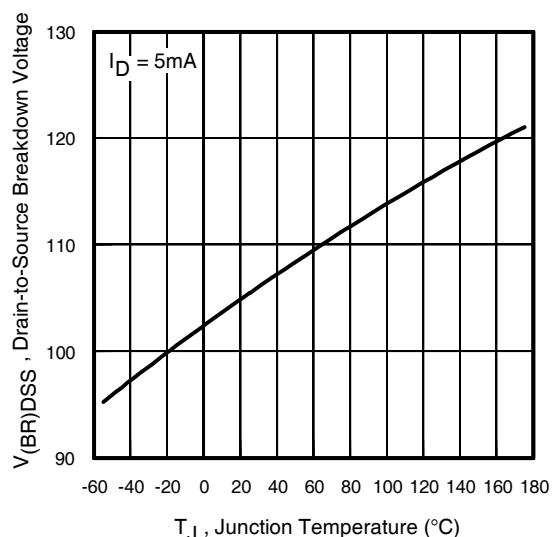


Fig 10. Drain-to-Source Breakdown Voltage

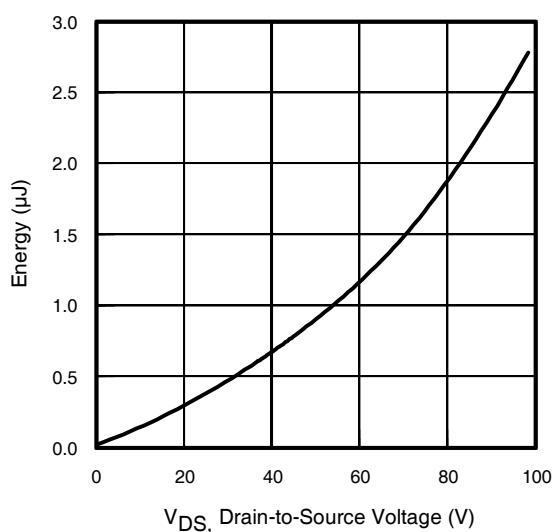


Fig 11. Typical  $C_{oss}$  Stored Energy

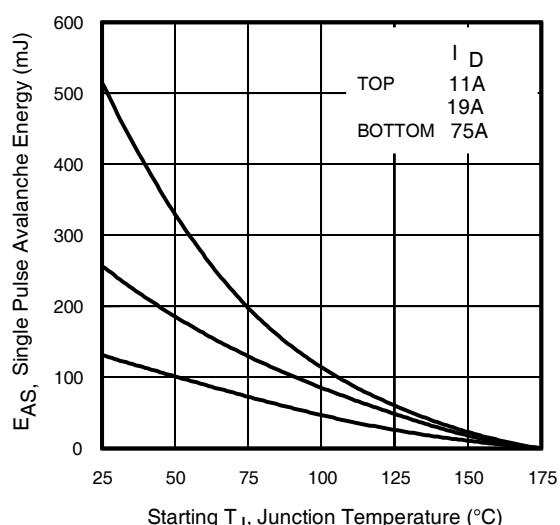


Fig 12. Maximum Avalanche Energy Vs. DrainCurrent

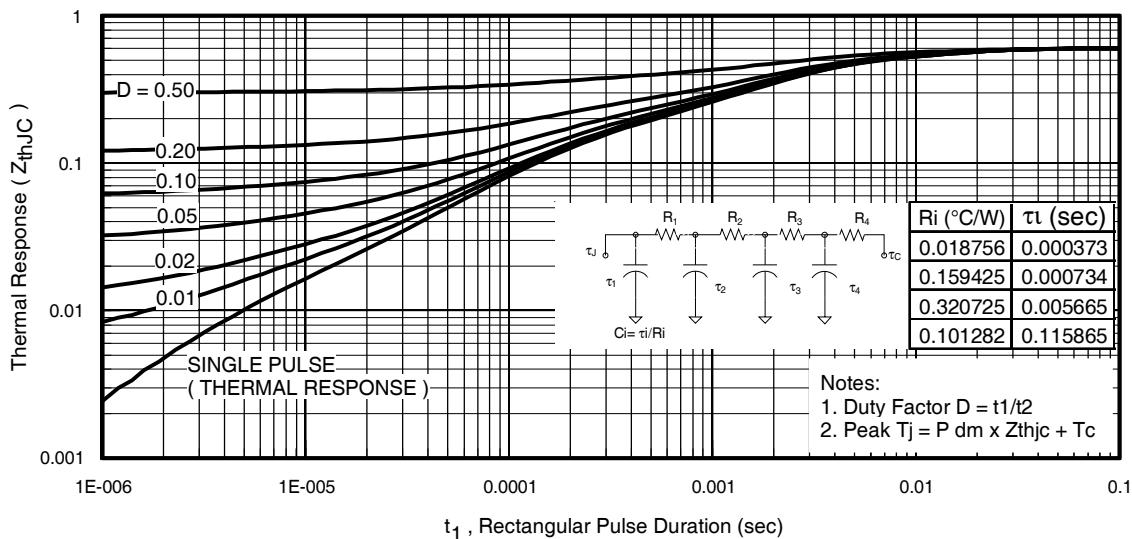


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

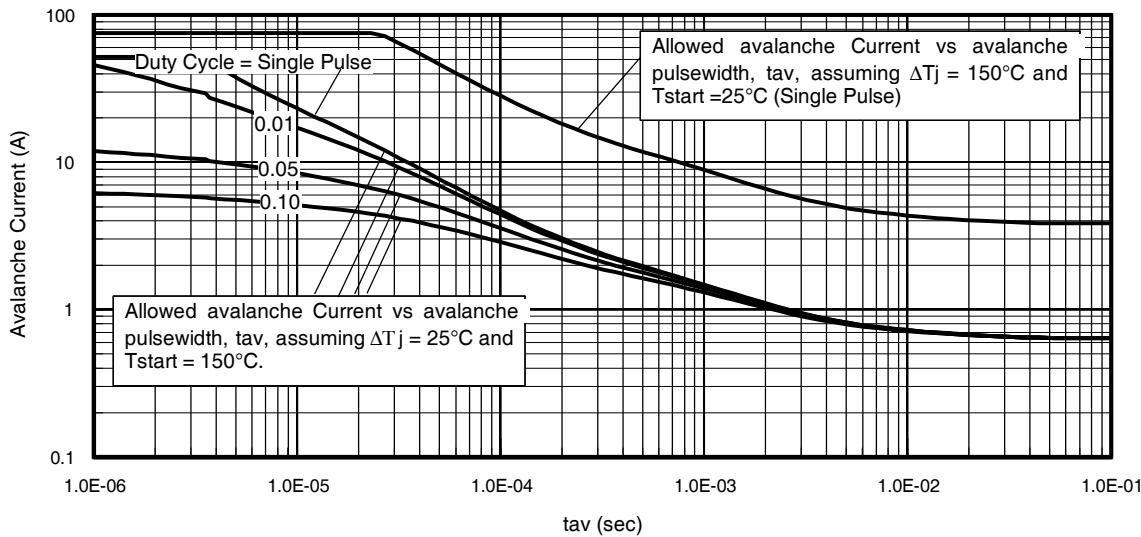


Fig 14. Typical Avalanche Current vs.Pulsewidth

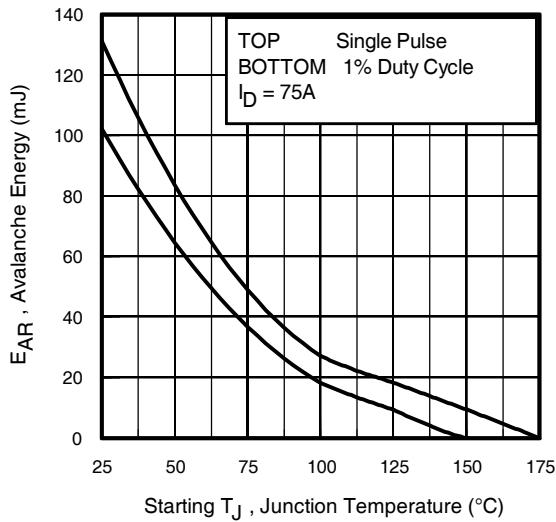


Fig 15. Maximum Avalanche Energy vs. Temperature

#### Notes on Repetitive Avalanche Curves , Figures 14, 15:

1. Avalanche failures assumption:  
Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as  $T_{jmax}$  is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 16a, 16b.
4.  $P_D(\text{ave})$  = Average power dissipation per single avalanche pulse.
5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6.  $I_{av}$  = Allowable avalanche current.
7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as  $25^\circ\text{C}$  in Figure 14).
- $t_{av}$  = Average time in avalanche.
- D = Duty cycle in avalanche =  $t_{av} \cdot f$
- $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)

$$P_D(\text{ave}) = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$$

$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

$$E_{AS(AR)} = P_D(\text{ave}) \cdot t_{av}$$

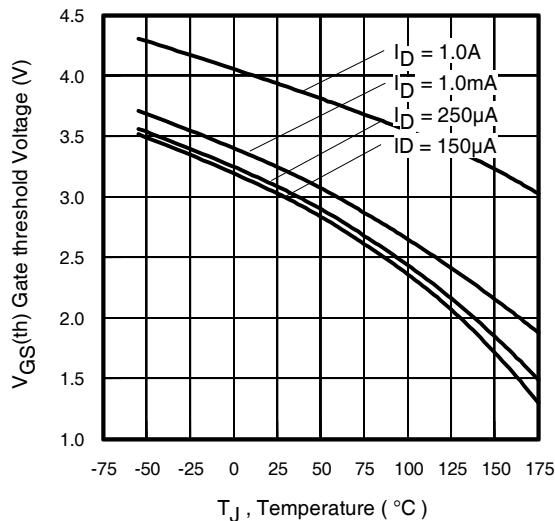


Fig. 16. Threshold Voltage Vs. Temperature

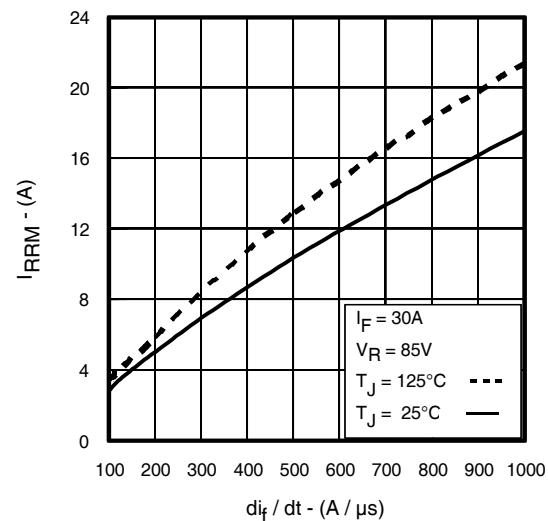


Fig. 17 - Typical Recovery Current vs.  $di_f/dt$

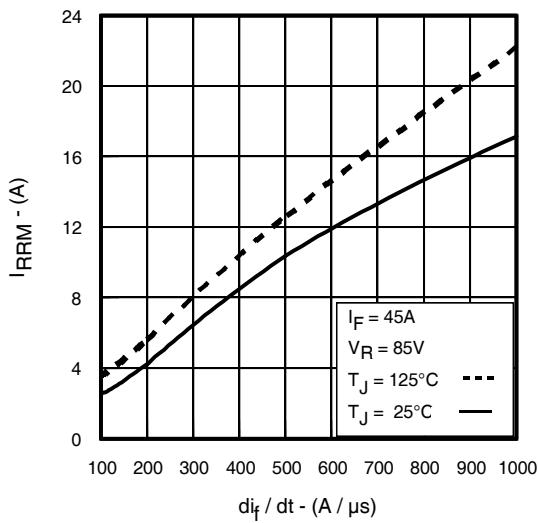


Fig. 18 - Typical Recovery Current vs.  $di_f/dt$

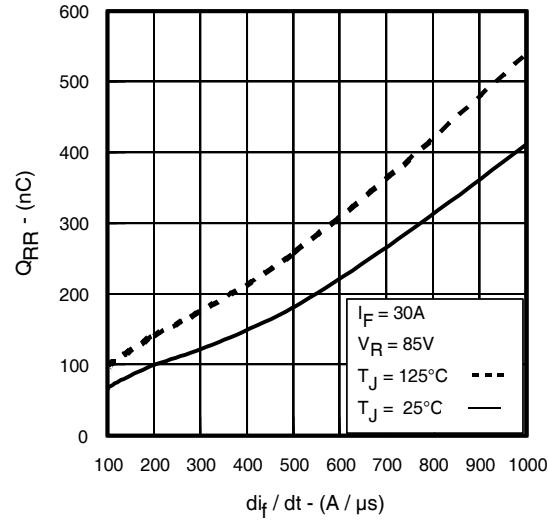


Fig. 19 - Typical Stored Charge vs.  $di_f/dt$

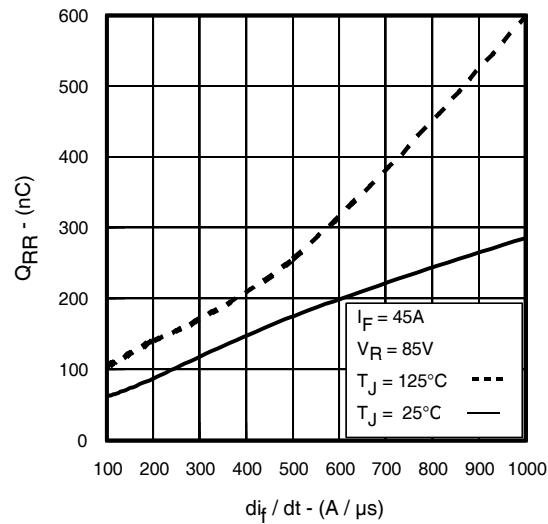
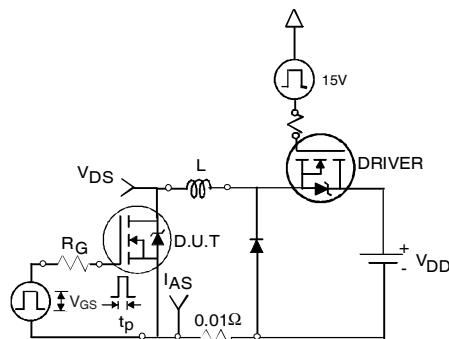
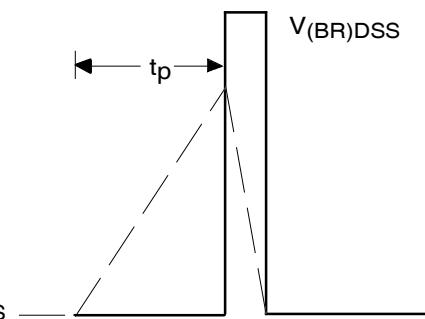
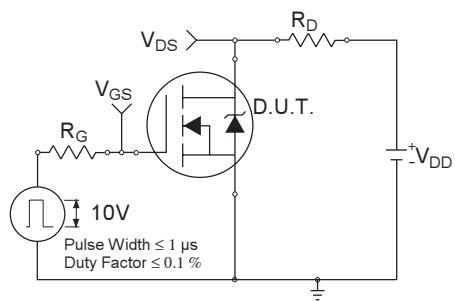
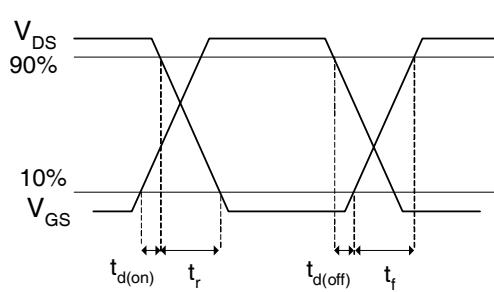
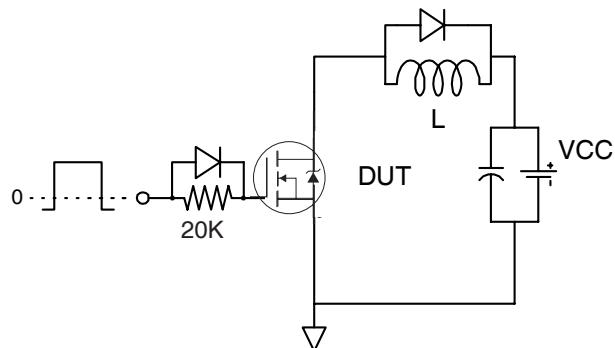
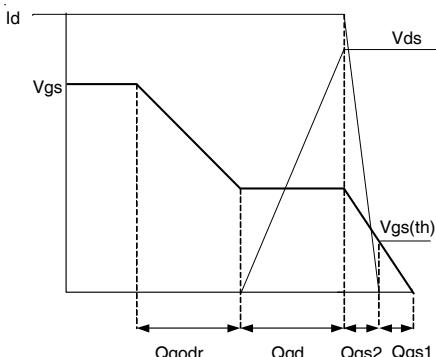
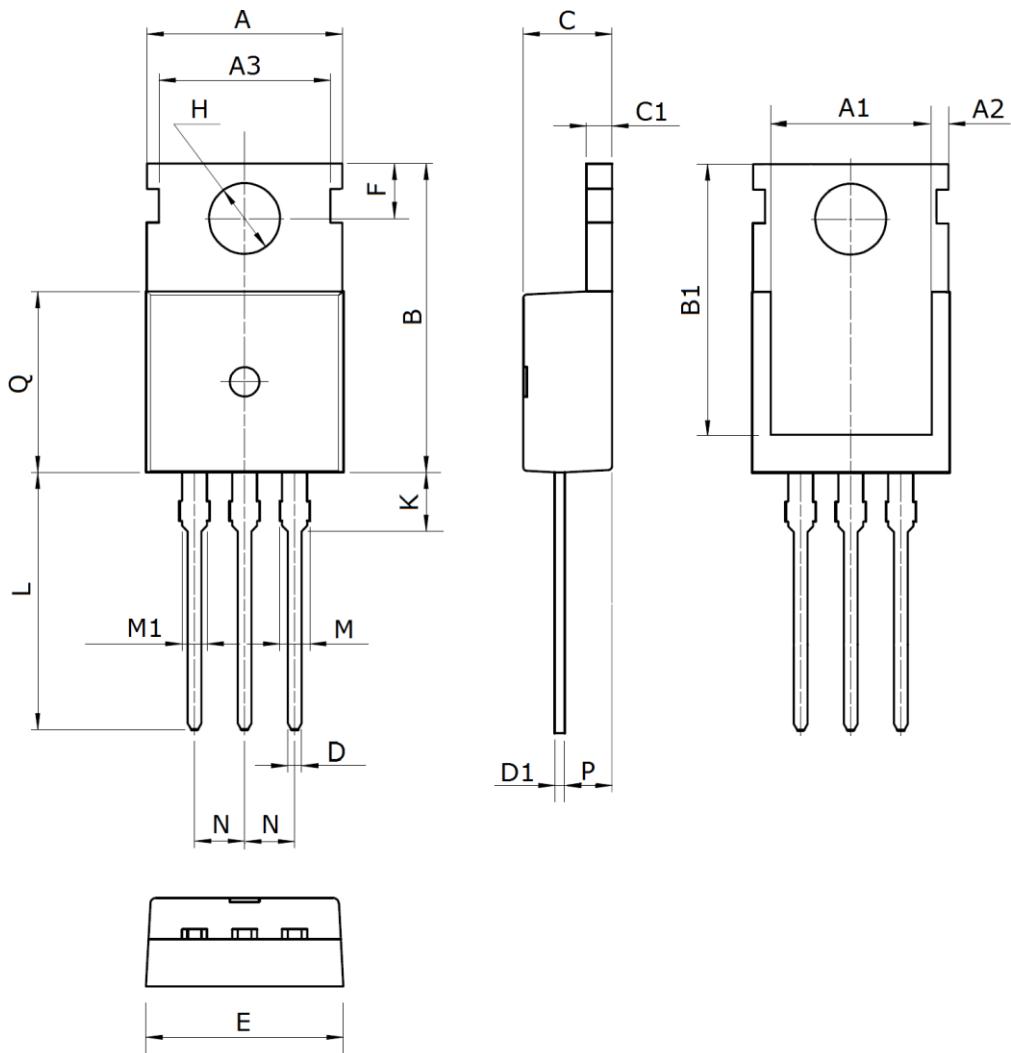


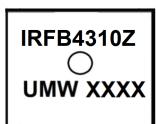
Fig. 20 - Typical Stored Charge vs.  $di_f/dt$

**Fig 21a.** Unclamped Inductive Test Circuit**Fig 21b.** Unclamped Inductive Waveforms**Fig 22a.** Switching Time Test Circuit**Fig 22b.** Switching Time Waveforms**Fig 23a.** Gate Charge Test Circuit**Fig 23b.** Gate Charge Waveform

**Package Mechanical Data TO-220**

Symbol	Dimensions (mm)	Symbol	Dimensions (mm)	Symbol	Dimensions (mm)
A	10.0±0.3	C1	1.3±0.2	L	13.2±0.4
A1	8.0±0.2	D	0.8±0.2	M	1.38±0.1
A2	0.94±0.1	D1	0.5±0.1	M1	1.28±0.1
A3	8.7±0.1	E	10.0±0.3	N	2.54(typ)
B	15.6±0.4	F	2.8 ±0.1	P	2.4±0.3
B1	13.2 ±0.2	H	3.6±0.1	Q	9.15±0.25
C	4.5±0.2	K	3.1±0.2		

## Marking



## Ordering information

Order code	Package	Baseqty	Deliverymode
UMW IRFB4310Z	TO-220	1000	Tube and box

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[DMN2990UFB-7B](#) [SSM3K35CT,L3F](#) [IPLK60R1K0PFD7ATMA1](#) [2N7002W-G](#) [MCAC30N06Y-TP](#) [IPWS65R035CFD7AXKSA1](#)  
[MCQ7328-TP](#) [SSM3J143TU,LXHF](#) [DMN12M3UCA6-7](#) [PJMF280N65E1\\_T0\\_00201](#) [PJMF380N65E1\\_T0\\_00201](#)  
[PJMF280N60E1\\_T0\\_00201](#) [PJMF600N65E1\\_T0\\_00201](#) [PJMF900N65E1\\_T0\\_00201](#)